

## 8-bit 35MSPS Video A/D Converter with Clamp Function

### Description

The CXD1179Q is an 8-bit CMOS A/D converter for video with synchronizing clamp function. The adoption of 2 step-parallel method achieves ultra-low power consumption and a maximum conversion speed of 35MSPS.

### Features

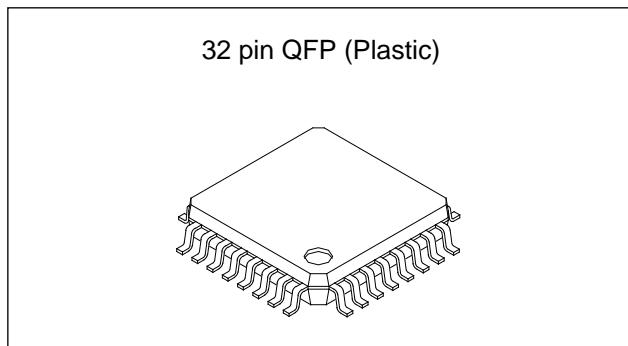
- Resolution: 8-bit  $\pm 1/2$ LSB (DL)
- Maximum sampling frequency: 35MSPS
- Low power consumption: 80mW (at 35MSPS typ.)  
(reference current excluded)
- Synchronizing clamp function
- Clamp ON/OFF function
- Reference voltage self bias circuit
- Input CMOS compatible
- 3-state TTL compatible output
- Single 5V power supply
- Low input capacitance: 8pF
- Reference impedance: 330Ω (typ.)

### Applications

Wide range of applications that require high-speed A/D conversion such as TV and VCR.

### Structure

Silicon gate CMOS IC



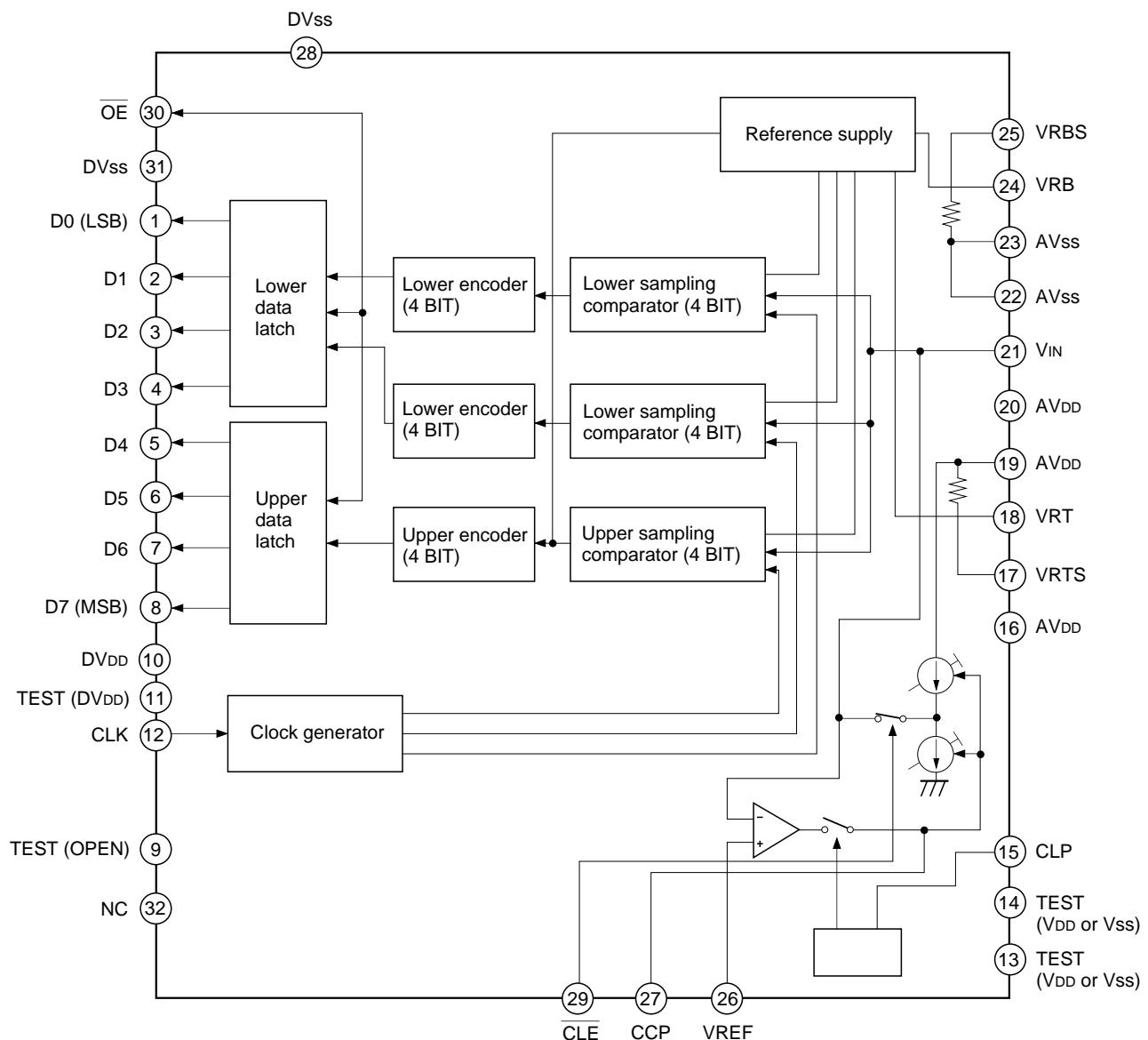
### Absolute Maximum Ratings (Ta = 25°C)

• Supply voltage	V <sub>DD</sub>	7	V
• Reference voltage	V <sub>RT</sub> , V <sub>RB</sub>	V <sub>DD</sub> + 0.5 to V <sub>SS</sub> - 0.5	V
• Input voltage	V <sub>IN</sub>	V <sub>DD</sub> + 0.5 to V <sub>SS</sub> - 0.5	V
• Input voltage	V <sub>I</sub>	V <sub>DD</sub> + 0.5 to V <sub>SS</sub> - 0.5	V
• Output voltage	V <sub>O</sub>	V <sub>DD</sub> + 0.5 to V <sub>SS</sub> - 0.5	V
• Storage temperature	T <sub>Stg</sub>	-55 to +150	°C

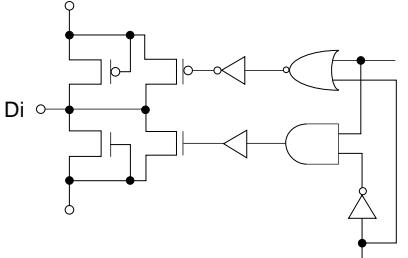
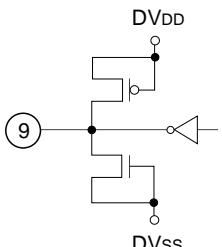
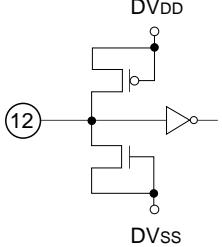
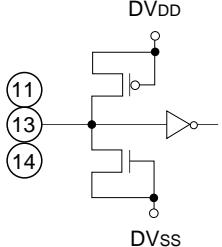
### Recommended Operating Conditions

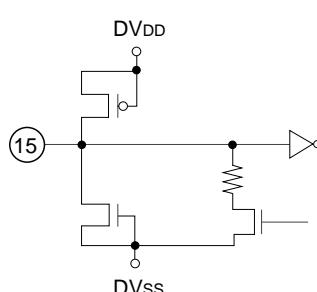
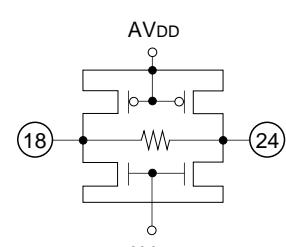
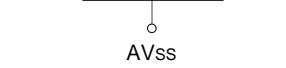
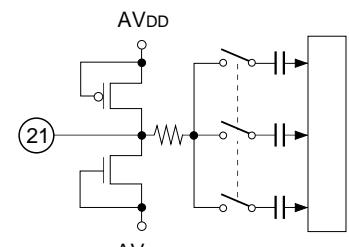
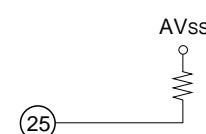
• Supply voltage	A <sub>VDD</sub> , A <sub>VSS</sub>	4.75 to 5.25	V
	D <sub>VDD</sub> , D <sub>VSS</sub>	D <sub>VSS</sub> - A <sub>VSS</sub>	mV
• Reference input voltage	V <sub>RB</sub>	0 and above	V
	V <sub>RT</sub>	2.7 and below	V
• Analog input	V <sub>IN</sub>	1.8V <sub>p-p</sub> above	
• Clock pulse width	T <sub>PW1</sub> , T <sub>PW2</sub>	13ns (min) to 1.1μs (max)	
• Operating ambient temperature	T <sub>opr</sub>	-40 to +85	°C

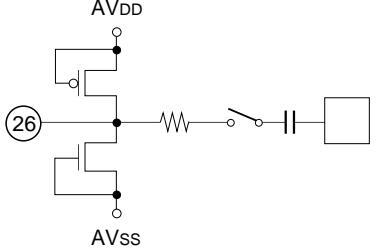
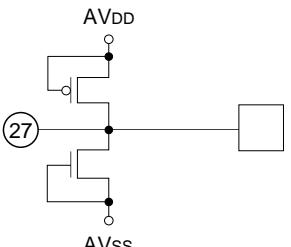
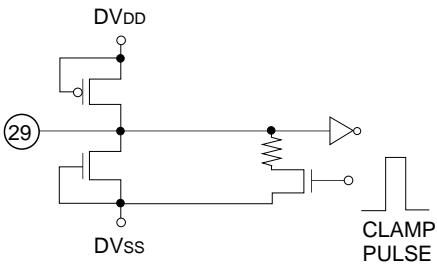
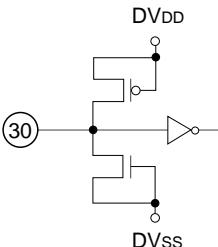
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**Block Diagram**

**Pin Description**

Pin No.	Symbol	Equivalent circuit	Description
1 to 8	D0 to D7		D0 (LSB) to D7 (MSB) output
9	TEST		Leave open during normal usage.
10	DVDD		Digital +5V
12	CLK		Clock input
11, 13, 14	TEST		Fix Pin 11 to VDD, Pins 13 and 14 to VDD or Vss during normal usage.

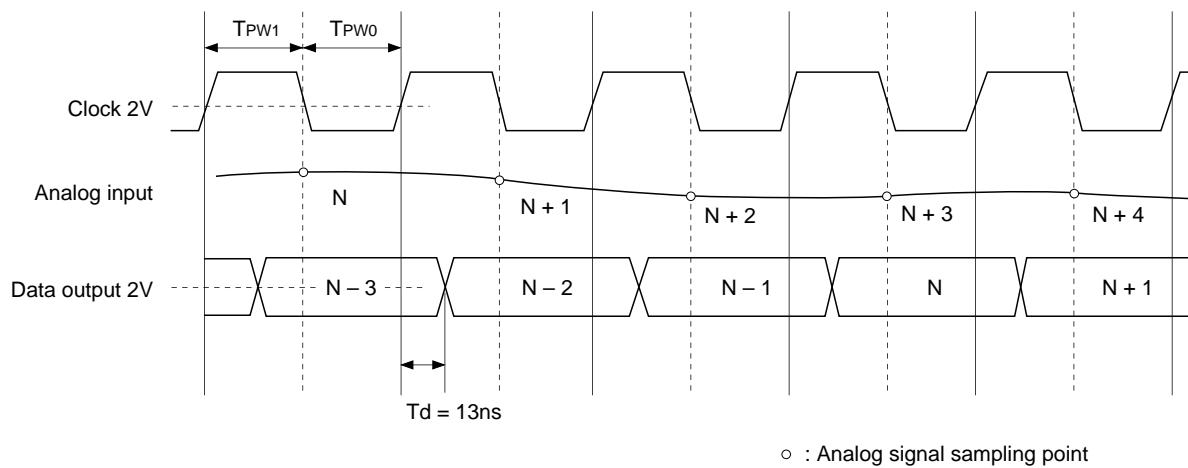
Pin No.	Symbol	Equivalent circuit	Description
15	CLP		Inputs clamp pulse to Pin 15 (CLP). Clamps the signal voltage during Low interval.
16, 19, 20	AVDD		Analog +5V
17	VRTS		Generates approximately +2.6V when shorted with VRT.
18	VRT		Reference voltage (top)
24	VRB		Reference voltage (bottom)
21	VIN		Analog input
22, 23	AVss		Analog ground
25	VRBS		Generates approximately +0.5V when shorted with VRB.

Pin No.	Symbol	Equivalent circuit	Description
26	VREF		Clamp reference voltage input. Clamps so that the reference voltage and the input signal during clamp interval are equal.
27	CCP		Integrates the clamp control voltage. The relationship between the changes in CCP voltage and in VIN voltage is positive phase.
28, 31	DVss		Digital ground
29	$\overline{CLE}$		The clamp function is enabled when $\overline{CLE}$ = Low. The clamp function is set to off and the converter functions as a normal A/D converter when $\overline{CLE}$ = High. The clamp pulse can be measured by connecting CLE to DVDD through a several hundred $\Omega$ resistor.
30	$\overline{OE}$		Data is output when $\overline{OE}$ = Low. Pins D0 to D7 are at high impedance when OE = High.
32	NC		NC pin

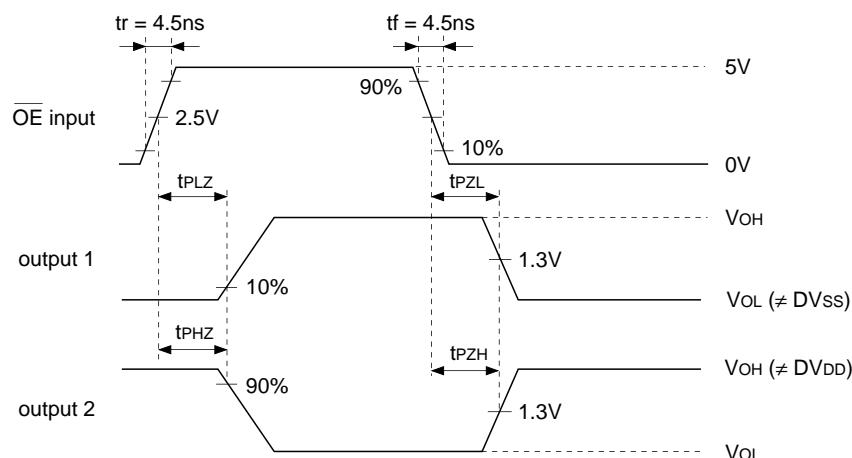
## Digital Output

The following table shows the relationship between analog input voltage and digital output code.

Input signal voltage	Step	Digital output code	
		MSB	LSB
$V_{RT}$	0	1 1 1 1 1 1 1 1	
:	:	:	
127	127	1 0 0 0 0 0 0 0	
:	128	0 1 1 1 1 1 1 1	
128	255	0 0 0 0 0 0 0 0	
:		:	
$V_{RB}$	255	0 0 0 0 0 0 0 0	



**Timing Chart I.**



**Timing Chart II.**

**Electrical Characteristics****Analog characteristics**(Fc = 35MSPS, V<sub>DD</sub> = 5V, V<sub>RB</sub> = 0.5V, V<sub>RT</sub> = 2.5V, Ta = 25°C)

Item	Symbol	Conditions		Min.	Typ.	Max.	Unit
Conversion speed	F <sub>c</sub>	V <sub>DD</sub> = 4.75 to 5.25V Ta = -40 to +85°C V <sub>IN</sub> = 0.5 to 2.5V f <sub>IN</sub> = 1kHz ramp		0.5		35	MSPS
Analog input band width (-1dB)	BW	Envelope			25		MHz
Offset voltage <sup>*1</sup>	E <sub>OT</sub>	Potential difference to V <sub>RT</sub>		-60	-40	-20	mV
	E <sub>OB</sub>	Potential difference to V <sub>RB</sub>		+55	+75	+95	
Integral non-linearity error	E <sub>L</sub>	End point			+0.5	+1.3 -1.0	LSB
Differential non-linearity error	E <sub>D</sub>				±0.3	±0.5	
Differential gain error	DG	NTSC 40 IRE mod ramp F <sub>c</sub> = 14.3MSPS			1		%
Differential phase error	DP				0.5		deg
Aperture jitter	t <sub>aj</sub>				30		ps
Sampling delay	t <sub>sd</sub>				2		ns
Clamp offset voltage <sup>*2</sup>	E <sub>oc</sub>	V <sub>IN</sub> = DC, PWS = 3μs	V <sub>REF</sub> = 0.5V	-20	0	+20	mV
			V <sub>REF</sub> = 2.5V	-30	-10	+10	
Clamp pulse delay	t <sub>cpd</sub>				25		ns

\*1 The offset voltage EOB is a potential difference between VRB and a point of position where the voltage drops equivalent to 1/2 LSB of the voltage when the output data changes from "00000000" to "00000001".

EOT is a potential difference between V<sub>RT</sub> and a potential of point where the voltage rises equivalent to 1/2LSB of the voltage when the output data changes from "11111111" to "11111110".

\*2 Clamp offset voltage varies individually. When using with R, G, B 3 channels, color sliding may be generated.

**DC characteristics**

(Fc = 35MSPS, VDD = 5V, VRB = 0.5V, VRT = 2.5V, Ta = 25°C)

Item	Symbol	Conditions		Min.	Typ.	Max.	Unit
Supply current	I <sub>DD</sub>	Fc = 35MSPS NTSC ramp wave input			16	22	mA
Reference pin current	I <sub>REF</sub>			4.5	6.1	8.7	mA
Analog input capacitance	C <sub>IN</sub>	V <sub>IN</sub> = 1.5V + 0.07Vrms			8		pF
Reference resistance (VRT to VRB)	R <sub>REF</sub>			230	330	440	Ω
Self-bias I	VRB <sub>1</sub>	Shorts VRB and VRBS Shorts VRT and VRTS		0.52	0.56	0.60	V
	VRT <sub>1</sub> – VRB <sub>1</sub>			1.96	2.10	2.24	
Self-bias II	VRT <sub>2</sub>	VRB = AGND Shorts VRT and VRTS		2.13	2.33	2.53	V
Digital input voltage	V <sub>IH</sub>	VDD = 4.75 to 5.25V Ta = -40 to +85°C		3.5			V
	V <sub>IL</sub>					0.5	
Digital input current	I <sub>IH</sub>	VDD = max	V <sub>IH</sub> = VDD			5	μA
	I <sub>IL</sub>		V <sub>IL</sub> = 0V			5	
Digital output current	I <sub>OH</sub>	OE = V <sub>SS</sub> VDD = min	V <sub>OH</sub> = VDD – 0.5V	-1.1	-2.5		mA
	I <sub>OL</sub>		V <sub>OL</sub> = 0.4V	3.7	6.5		
	I <sub>OZH</sub>	OE = VDD VDD = max	V <sub>OH</sub> = VDD			16	μA
	I <sub>OZL</sub>		V <sub>OL</sub> = 0V			16	

**Timing**

(Fc = 35MSPS, VDD = 5V, VRB = 0.5V, VRT = 2.5V, Ta = 25°C)

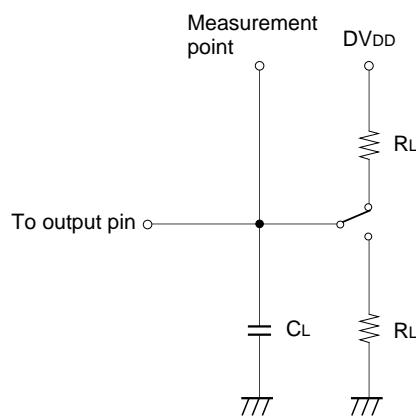
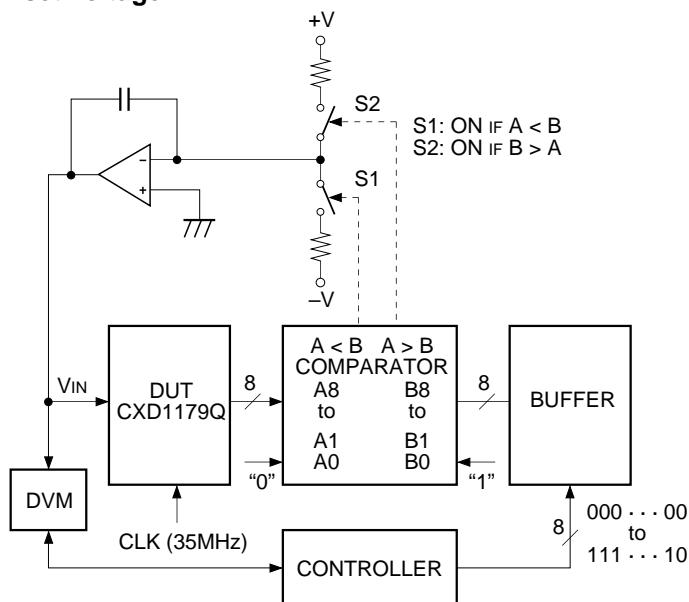
Item	Symbol	Conditions		Min.	Typ.	Max.	Unit
Output data delay	T <sub>DL</sub>	With TTL 1 gate and 10pF load VDD = 4.75 to 5.25V Ta = -40 to +85°C		7	13	18	ns
Tri-state output enable time	t <sub>PZH</sub> t <sub>PZL</sub>	R <sub>L</sub> = 1kΩ, C <sub>L</sub> = 15pF OE = 5V → 0V VDD = 4.75 to 5.25V Ta = -40 to +85°C		5	8	14	ns
Tri-state output disable time	t <sub>PHZ</sub> t <sub>PLZ</sub>	R <sub>L</sub> = 1kΩ, C <sub>L</sub> = 15pF OE = 0V → 5V VDD = 4.75 to 5.25V Ta = -40 to +85°C		4	6.5	11	ns
Clamp pulse width*1	t <sub>CPW</sub>	Fc = 14MSPS, C <sub>IN</sub> = 10μF for NTSC wave		1.75	2.75	3.75	μs

\*1 The clamp pulse width is for NTSC as an example. Adjust the rate to the clamp pulse cycle (1/15.75kHz for NTSC) for other processing systems to equal the values for NTSC.

**Electrical Characteristics Measurement Circuit**

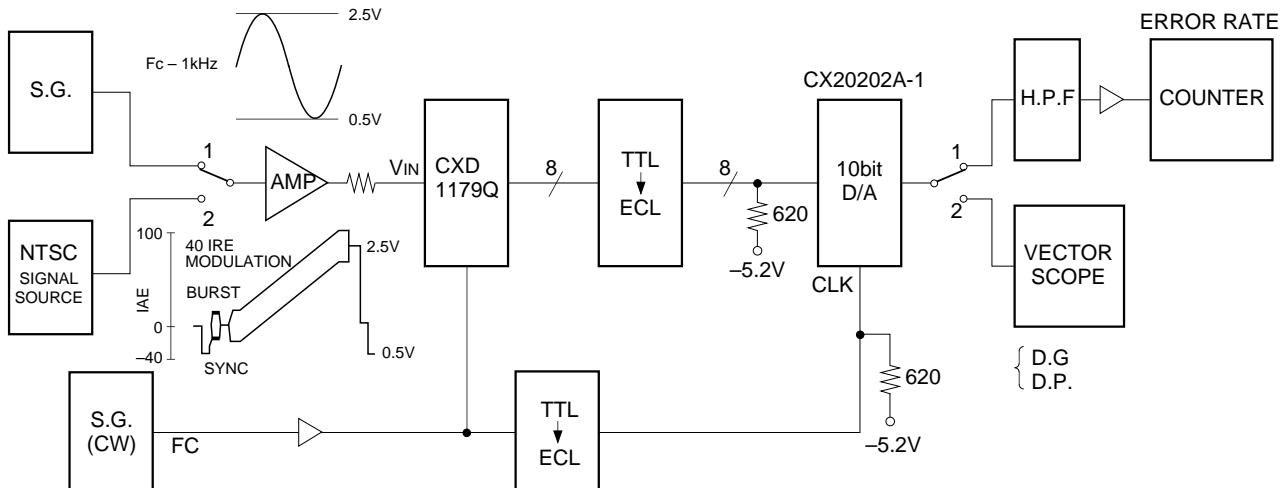
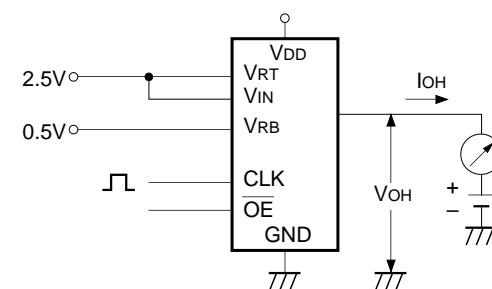
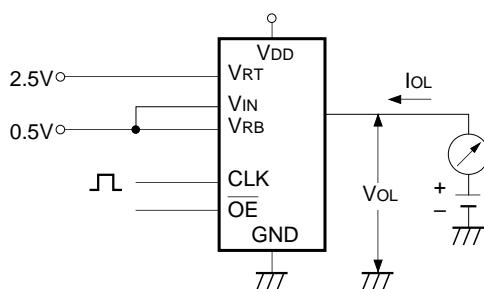
**Integral non-linearity error**  
**Differential non-linearity error**  
**Offset voltage**

**Tri-state output measurement circuit**



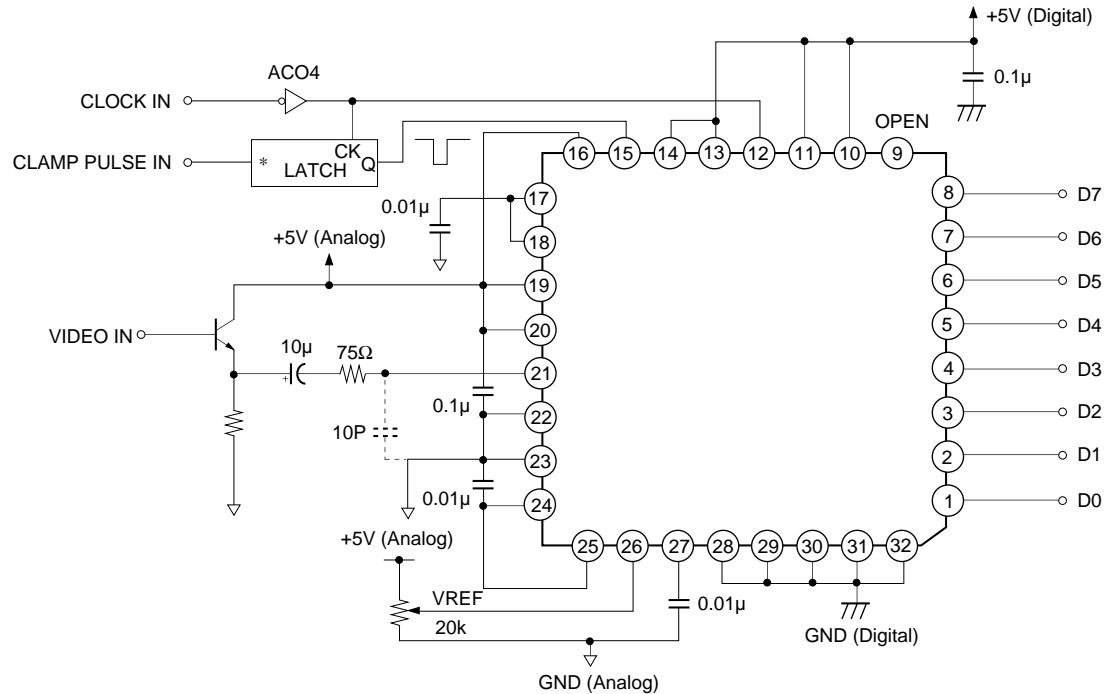
Note) CL includes capacitance of the probe and others.

**Maximum operational speed**  
**Differential gain error**  
**Differential phase error**

**Digital output current measurement circuit**

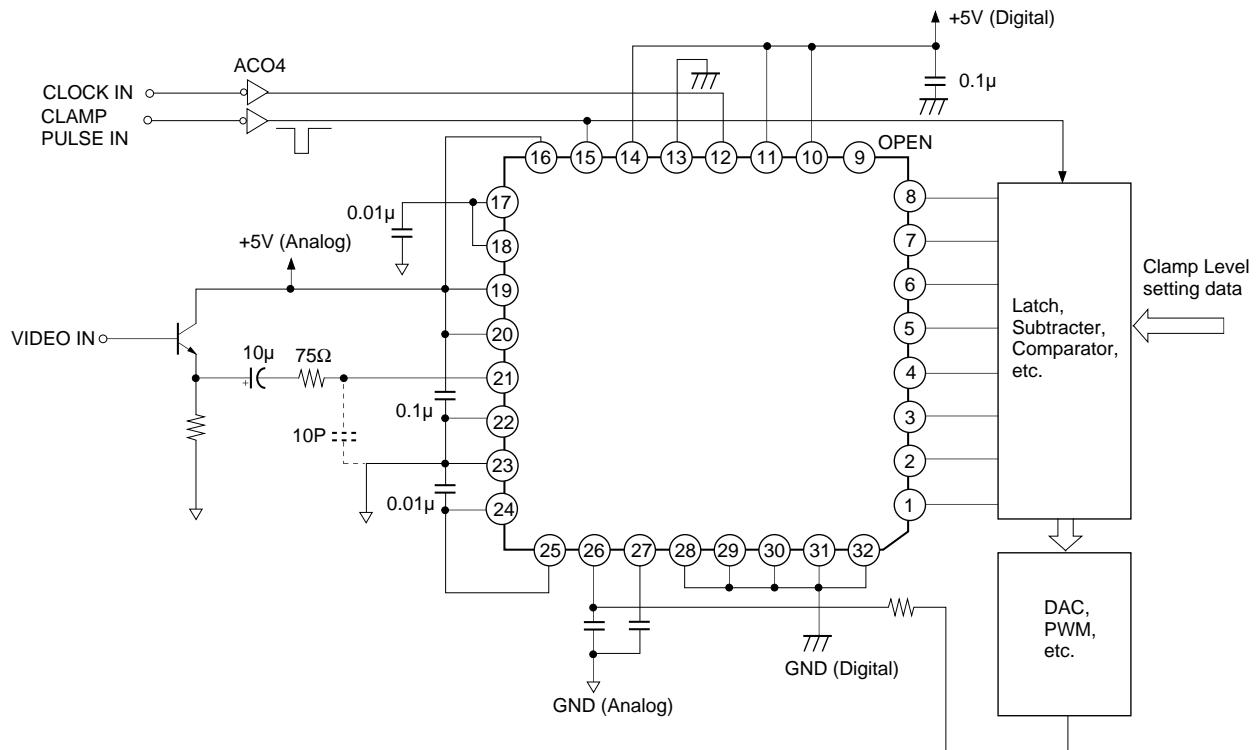
## Application Circuit

### (1) When clamp is used (self bias used)

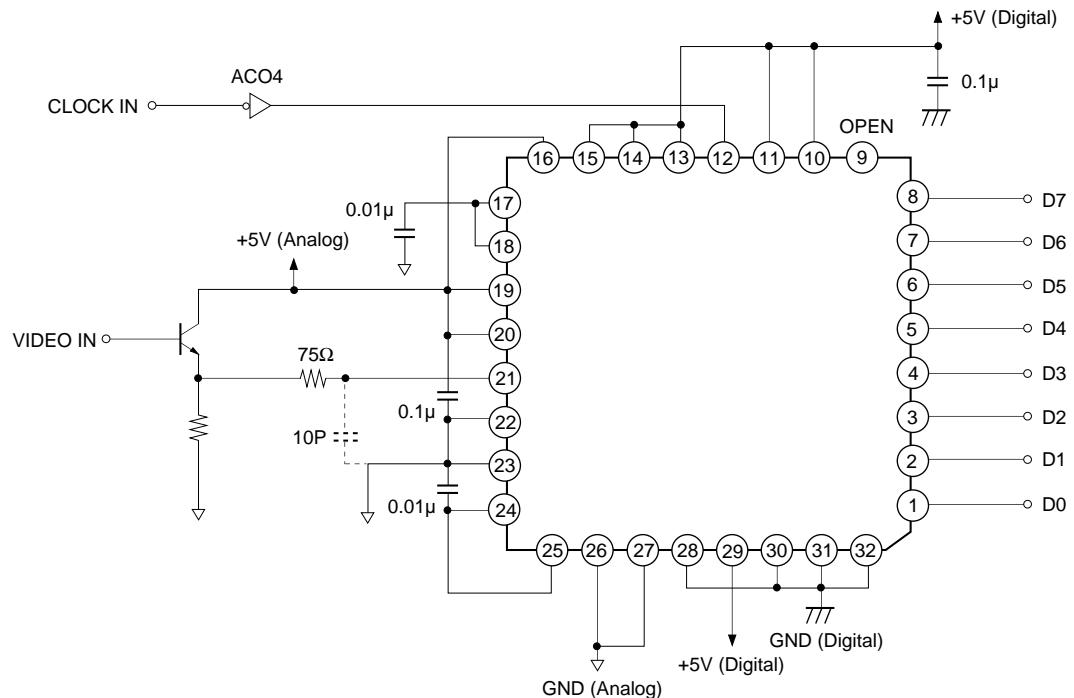


\* The clamp pulse is latched by the sampling clock of ADC, but that is not necessary for basic clamp operation. However, slight small beat may be generated as vertical sag according to the relationship between the sampling frequency and the clamp pulse frequency. At such time, the latch circuit is effective in this case.

### (2) Digital clamp (self bias used)



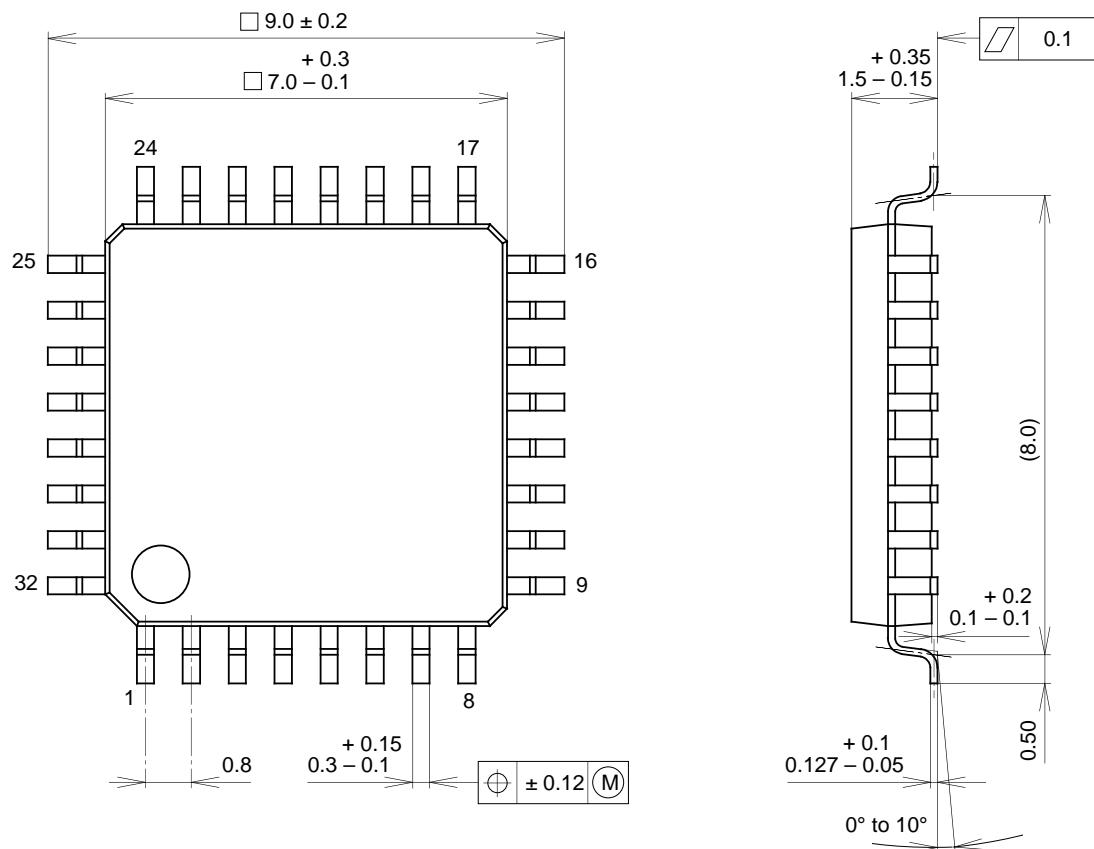
### (3) When clamp is not used (self bias used)



## Package Outline

Unit: mm

32PIN QFP (PLASTIC)



SONY CODE	QFP-32P-L01
EIAJ CODE	*QFP032-P-0707-A
JEDEC CODE	-----

PACKAGE MATERIAL	EPOXY RESIN
LEAD TREATMENT	SOLDER PLATING
LEAD MATERIAL	42 ALLOY
PACKAGE WEIGHT	0.2g